

INTERNATIONAL STANDARD

GROUP SAFETY PUBLICATION

AMENDMENT 1

**Safety requirements for electrical equipment for measurement, control and laboratory use –
Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement**

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**Safety requirements for electrical equipment for measurement, control and laboratory use –
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INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

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Warning! Make sure that you obtained this publication from an authorized distributor.

FOREWORD

This amendment has been prepared by IEC technical committee 66: Safety of measuring, control and laboratory equipment.

The text of this standard is based on the following documents:

FDIS	Report on voting
66/664/FDIS	66/670/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

Title

Replace the part title as follows:

Part 031: Safety requirements for hand-held and hand-manipulated probe assemblies for electrical test and measurement

1 Scope and object

1.1.1 Probe assemblies included in scope

Figure 4 – Examples of Type D probe assemblies

Delete, in key 3, the words "or clamp".

3 Terms and definitions

3.1.1

TERMINAL

Note 1 to entry:

Delete the word “connectors,”.

3.1.5

CONNECTOR

Delete, in the definition, the words “a CONNECTOR of” so that the end of the sentence will read:

“...to connect to a TERMINAL of the equipment or to another probe assembly”.

3.4.11

MEASUREMENT CATEGORY

Replace the existing text of the definition with the following:

classification of testing and measuring circuits according to the types of mains to which they are intended to be connected

4 Tests

4.3.9 Duty cycle

Replace the existing title of 4.3.9 with the following:

4.3.9 Short-term or intermittent operation

4.4.4.2 Temperature

Replace the existing second paragraph with the following:

This temperature is determined by measuring the temperature rise of the surface or part and adding it to the ambient temperature of 40 °C, or to the maximum RATED ambient temperature if higher.

4.5.2 Fuses

Replace, in the fourth sentence of the second paragraph, the word “MAINS” (in SMALL CAPS) with “mains” (in regular font).

5 Marking and documentation

5.1.5 RATING

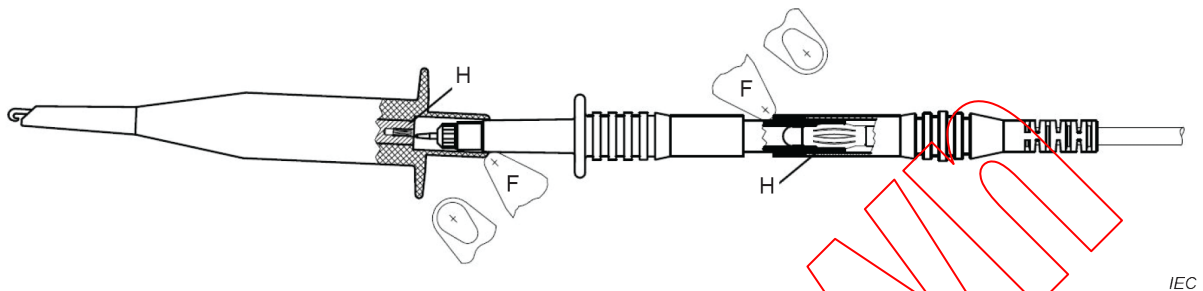
Replace, in list item a) of the first paragraph, the words “(see also 5.4.3 f) and g))” with “(see also 5.4.3 k))”.

6 Protection against electric shock

6.2.2 Examination

Figure 6 – Methods for determination of ACCESSIBLE parts (see 6.2) and for voltage tests (see 6.4.2)

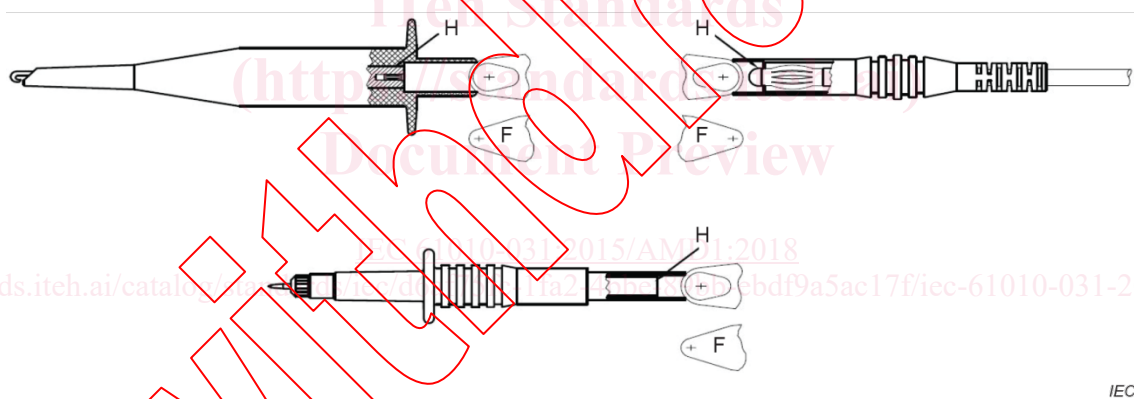
Replace the existing subfigures 6c and 6d with the following new subfigures:



Connecting parts are partially mated so as just to make electrical contact while allowing maximum access to the test finger.

Note the two possible positions of the test finger.

Figure 6c – Partially mated probe assemblies (see 6.2 and 6.4.2 b)



Key

F rigid test finger (see Figure B.1)

H potentially HAZARDOUS LIVE part

Note the two possible positions of the test finger.

Figure 6d – Unmated parts of a probe assembly (see 6.2 and 6.4.2 c)

6.3.4.1 General

Replace, in the first paragraph, the existing list with the following:

- the probe body;
- hand-held or hand-manipulated parts of each CONNECTOR;
- 150 mm \pm 20 mm of the PROBE WIRE or the maximum length of the cable whichever is shorter;
- other hand-held or hand-manipulated parts.

Figure 8 – Voltage and touch current measurement

Delete, in the text of key item 2c, the words “(see 12.3.2)”.

6.3.4.2 Probe assemblies with floating outer conductors

Figure 10 – Voltage and touch current measurement with shielded test probe

Delete, in the text of key item 2c, the words “(see 12.3.2)”.

6.3.4.3 High frequency test probes

Replace, in the fourth paragraph, “the circuit from A.3” with “the circuit from Figure A.3”.

6.4.1 General

Replace, in the third paragraph, the existing list with the following list:

- a) DOUBLE INSULATION, consisting of BASIC INSULATION plus SUPPLEMENTARY INSULATION (see 6.4.6)
- b) BASIC INSULATION plus impedance (see 6.4.4);
- c) REINFORCED INSULATION (see 6.4.6);
- d) PROTECTIVE IMPEDANCE (see 6.4.5).

6.4.2 CONNECTORS

Add, at the end of the sentence of 6.4.2 c) 2), “(see Figure 5)”.

6.4.3.2 Protection by a PROTECTIVE FINGERGUARD

Replace the existing third paragraph with the following:

The height of the PROTECTIVE FINGERGUARD from the side where the fingers are intended to be applied shall be at least 2 mm.

6.4.3.4 Protection by tactile indicator

Replace the existing first paragraph with the following:

SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY II or without MEASUREMENT CATEGORY for maximum 300 V which require finger pressure at about 90° to the axis of the clip are acceptable without a PROTECTIVE FINGERGUARD, provided that there is a tactile indicator to indicate the limit of safe access for the OPERATOR.

6.4.3.5 PROBE TIPS used as CONNECTORS

Replace the text with the following text:

PROBE TIPS which can be used as CONNECTORS and are intended to be connected to specified accessories (for example to a SPRING-LOADED CLIP) shall, in combination with those accessories, also meet the requirements for CONNECTORS in fully-mated position and partially-mated position (see 6.4.2 a) and b)).

6.5.1.2.4 SOLID INSULATION

Delete the entire subclause including Table 4, Table 5, Figure 15, Figure 16 and Figure 17.

Add the following new subclause:

6.5.1.3 Solid insulation

The term “solid insulation” is used to describe many different types of construction, including monolithic blocks of insulating material and insulation subsystems composed of multiple insulating materials, organized in layers or otherwise.

The electric strength of a thickness of solid insulation is considerably greater than that of the same thickness of air. The insulating distances through solid insulation are therefore typically smaller than the distances through air. As a result, electric fields in solid insulation are typically higher, and often are less homogeneous.

Solid insulation material may contain gaps or voids. When a solid insulation system is constructed from layers of solid materials, there are also likely to be gaps or voids between layers. These voids will perturb the electric field so that a disproportionately large part of the electric field is located in the void, potentially causing ionization within the void, resulting in partial discharge. These partial discharges will influence the adjacent solid insulation and may reduce its service life.

Solid insulation is not a renewable medium: damage is cumulative over the life of the equipment. Solid insulation is also subject to ageing and to degradation from repeated high voltage testing.

Conformity is checked as specified in 6.5.2.5 and 6.5.2.6.

6.5.2.2 CLEARANCES for probe assemblies of MEASUREMENT CATEGORIES II, III and IV

Replace the existing Table 6 with the following:

Table 6 – CLEARANCES of probe assemblies RATED for MEASUREMENT CATEGORIES

Nominal a.c. r.m.s. line-to-neutral or d.c. voltage of mains to which the probe assembly is designed to be connected V	CLEARANCE mm					
	BASIC INSULATION and SUPPLEMENTARY INSULATION			REINFORCED INSULATION		
	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV
≤ 50	0,04	0,1	0,5	0,10	0,32	1,4
> 50 ≤ 100	0,1	0,5	1,5	0,32	1,4	3,0
> 100 ≤ 150	0,5	1,5	3,0	1,4	3,0	6,0
> 150 ≤ 300	1,5	3,0	5,5	3,0	6,0	10,4
> 300 ≤ 600	3,0	5,5	8	6,0	10,4	15
> 600 ≤ 1 000	5,5	8	14	10,4	15	23,9
> 1 000 ≤ 1 500	8	11	18	16	22	36
> 1 500 ≤ 2 000	14	18	22	28	36	44
> 2 000 ≤ 3 000	18	22	25	36	44	50

Replace, in the conformity statement, the word “clearance” with “CLEARANCE” (in SMALL CAPS).

6.5.2.3.1 General

Replace, in the second paragraph, the words “required clearance” with “required CLEARANCE”.

Add the following two new subclauses, Table 4, Table 5, Table 14, Figure 15, Figure 16 and Figure 17:

6.5.2.5 Solid insulation of probe assemblies RATED for MEASUREMENT CATEGORIES

6.5.2.5.1 General

6.5.2.5.1.1 Solid insulation of probe assemblies RATED for MEASUREMENT CATEGORIES shall withstand the electrical and mechanical stresses that may occur in NORMAL USE and in all RATED environmental conditions (see 1.4) during the intended life of the probe assembly.

The manufacturer should take the expected life of the probe assembly into account when selecting insulating materials.

Conformity is checked by both of the following tests:

- the a.c. voltage test of 6.6.5.1 with a duration of at least 5 s using the applicable test voltage of Table 4 or the impulse voltage test of 6.6.5.3 using the applicable test voltage of Table 14;
- the a.c. voltage test of 6.6.5.1 or if stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the test voltage determined by 6.5.2.5.1.2.

NOTE Test a) checks the effects of transient overvoltages, while test b) checks the effects of long-term stress of solid insulation.

Table 4 – a.c. test voltages for testing electric strength of solid insulation in probe assemblies RATED for MEASUREMENT CATEGORIES

Nominal a.c. r.m.s. line-to-neutral or d.c. voltage of mains being measured V	a.c. test voltage V r.m.s					
	BASIC INSULATION and SUPPLEMENTARY INSULATION			REINFORCED INSULATION		
	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV
≤ 50	370	500	840	500	720	1300
> 50 ≤ 100	500	840	1 400	720	1 300	2 200
> 100 ≤ 150	840	1 400	2 200	1 300	2 200	3 500
> 150 ≤ 300	1 400	2 200	3 300	2 200	3 500	5 100
> 300 ≤ 600	2 200	3 300	4 300	3 500	5 100	7 000
> 600 ≤ 1 000	3 300	4 300	6 600	5 100	7 000	10 000
> 1 000 ≤ 1 500	4 300	5 400	8 200	7 400	9 700	15 000
> 1 500 ≤ 2 000	6 600	8 200	9 700	12 000	15 000	18 000
> 2 000 ≤ 3 000	8 200	9 700	11 000	15 000	18 000	20 000

Table 14 – Impulse test voltages for testing electric strength of solid insulation in probe assemblies RATED for MEASUREMENT CATEGORIES

Nominal a.c. r.m.s. line-to-neutral or d.c. voltage of mains being measured V	Impulse test voltage V peak					
	BASIC INSULATION and SUPPLEMENTARY INSULATION			REINFORCED INSULATION		
	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV
≤ 50	500	800	1 500	800	1 280	2 400
> 50 ≤ 100	800	1 500	2 500	1 280	2 400	4 000
> 100 ≤ 150	1 500	2 500	4 000	2 400	4 000	6 400
> 150 ≤ 300	2 500	4 000	6 000	4 000	6 400	9 600
> 300 ≤ 600	4 000	6 000	8 000	6 400	9 600	12 800
> 600 ≤ 1 000	6 000	8 000	12 000	9 600	12 800	19 200
> 1 000 ≤ 1 500	8 000	10 000	15 000	13 500	17 900	27 100
> 1 500 ≤ 2 000	12 000	15 000	18 000	21 400	27 100	32 000
> 2 000 ≤ 3 000	15 000	18 000	20 000	27 100	32 000	36 000

6.5.2.5.1.2 Test voltage values for testing long term stress of solid insulation are determined as follows:

The test voltage for BASIC INSULATION and SUPPLEMENTARY INSULATION is calculated from:

$$U_T = A \times U_N + B$$

where

U_T is the test voltage;

U_N is the nominal a.c. r.m.s. line-to-neutral or d.c. voltage of mains being measured;